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NASA TM X-63903

# A METHOD OF TREATING THE NON-GREY ERROR IN TOTAL EMITTANCE MEASUREMENTS

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JANUARY 1970



**GODDARD SPACE FLIGHT CENTER**  
**GREENBELT, MARYLAND**

FACILITY FORM 602

~~1740-27320~~ (PAGES)

TMX-63903  
(NASA CR OR TMX OR AD NUMBER)

(THRU)

(CODE)

(CATEGORY)

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# A Method Of Treating The Non-Grey Error In

## Total Emittance Measurements

J. B. Heaney and J. H. Henninger

### ABSTRACT

In techniques presently available for the rapid determination of total emittance, the sample is generally exposed to surroundings that are at a different temperature than the sample's surface. When the infrared spectral reflectance of the surface is spectrally selective, an error is introduced into the total emittance values so determined. Surfaces of aluminum overcoated with oxides of various thicknesses fall into this class and are often used as temperature control coatings on satellites which requires that their emittances be accurately known. The magnitude of the error was calculated for Alzak and silicon oxide coated aluminum and is shown to be dependent on the thickness of the oxide. The results demonstrate that because the magnitude of the error is thickness dependent, it is generally impossible or impractical to eliminate it by calibrating the measuring device.

## A METHOD OF TREATING THE NON-GREY ERROR IN TOTAL EMITTANCE MEASUREMENTS

### INTRODUCTION

One problem that arises in the area of satellite design is the variation in material properties between samples chosen for study and pieces actually used in fabrication. Because of the difficulties involved in determining material properties after assembly, engineers often rely on measurements obtained on materials prior to assembly or on data taken from samples selected as being representative of the material in use. This is especially crucial for thermal control surfaces and solar cell arrays where system performance is strongly dependent upon the surface condition as defined by its solar absorptance,  $\alpha$ , and thermal emittance,  $\epsilon_T$ .

Surface materials used in the design of spacecraft thermal control systems are selected on the basis of their having solar absorptance and thermal emittance values compatible with the mission's temperature requirements. It has been shown that highly reflecting aluminum surfaces overcoated with dielectric films of varying thickness can produce coatings that have a wide range of  $\alpha/\epsilon_T$  values.<sup>1,2</sup> These dielectric films are non-absorbing in the solar region but rely on a combination of interference and absorption effects to give high infrared emittances. The  $\alpha$  is essentially independent of thickness, while  $\epsilon_T$  increases steadily with increasing thickness of the dielectric film. For a certain range of thickness,  $\epsilon_T$  is strongly thickness dependent so that a slight change in thickness can cause a rather large change in emittance. This means that the thickness must be

carefully controlled and monitored. Surfaces of this type exhibit a spectrally varying infrared reflectance as a result of the combination of absorption and interference effects. A compensating form of temperature control often occurs as a byproduct of this arrangement since the emittance increases with temperature when the proper dielectric film thickness is chosen.

The emittance is a sensitive function of the dielectric film thickness because the infrared reflectance is determined by the thickness controlled depth of absorption bands. This spectral selectivity of the infrared reflectance gives rise to the non-grey error that exists in devices commonly used for the rapid determination of total emittance and it has been shown that this error can be quite large.<sup>3</sup> Although it is possible in many cases to eliminate this error through proper calibration with samples of known emittance, it will be shown that when the emittance is thickness dependent, calibration is either impossible or impractical. Therefore, the magnitude of the error must be determined for the type of device used. The choice of instrumentation is generally intended to satisfy the engineer's need to correlate laboratory sample data with measurements performed on actual flight hardware. There are several commercially available instruments which permit the  $\epsilon_T$  of a spacecraft surface to be determined after assembly in a rapid non-destructive manner. They all involve the determination of total emittance and are therefore subject to the non-grey error.

## EXPERIMENTAL TECHNIQUES

Total emittance measurements were performed in this investigation with a Gier-Dunkle Model DB-100 portable infrared reflectometer. This device produces a weighted value of the reflectance of an opaque sample from which the

emittance is determined. The measurement is performed relative to high and low reflectance standards. It is instantaneous and is independent of surface temperature over the range 20° - 60°C. Through the use of a selective filter, the non-grey error is minimized although it will be shown in the following calculations that it has not been eliminated. The operating principles and design details of a prototype of this device have been presented in the literature.<sup>4</sup> However, as this analysis proceeds it will be necessary to provide a cursory description of the instrument's features for clarity and in support of the arguments.

The values of relative weighted reflectance are obtained from hohlraum measurements. Any surface covering the sample port is alternately exposed to omni-directional radiation emitted by hot and cold semicylinders acting as black body cavities. The radiant flux from the exposed area that reaches the detector is given by

$$\int_{A_D} \int_{A_S} I_S \frac{\cos \theta_S \cos \theta_D}{r_{SD}^2} dA_S dA_D$$

where

$A_S$  = illuminated area of the sample

$A_D$  = effective viewing aperture area of the detector

$\theta_S, \theta_D$  = angle between the indicated surface normals and the path,  $r_{SD}$ , followed by the radiant flux.

$I_S$  = Hohlraum radiation reflected by the surface in the direction  $r_{SD}$ .

Since the illuminated area is viewed by the detector in a near-normal direction, all parameters dealt with in the following analysis are considered to be averaged over the solid angle subtended by this area. For example, when the term reflectance,  $\rho$ , is used it is understood that

$$\rho = \frac{\int_{A_D} \int_{A_S} \rho(\theta) \frac{\cos \theta_S \cos \theta_D}{r_{SD}^2} dA_S dA_D}{\int_{A_D} \int_{A_S} \frac{\cos \theta_S \cos \theta_D}{r_{SD}^2} dA_S dA_D}$$

where  $\rho(\theta)$  is the more correct angular dependent parameter. For the infrared region considered here and for the narrow viewing angle used in this device, it is safe to say that  $\rho = \rho(\theta)$  and  $\epsilon = \epsilon(\theta)$ .

When a test surface covers the viewing port of the instrument's sensing head and is irradiated by the rotating semicylindrical cavities, an alternating signal is produced in the detector due to the fact that the cavities are at different temperatures. The intensity of radiant flux coming from the direction of the sample when irradiated by the hotter cavity is:

$$I_{S_H} = \epsilon_S(T_S) \tau(T_S) \sigma T_S^4 + \rho_S(T_S, T_H) \tau(T_S, T_H) \sigma T_H^4 + C. \quad (1)$$

where

$\epsilon_S(T_S)$  = near normal emittance for a sample at temperature  $T_S$ .

$\rho_S(T_S, T_H)$  = near normal reflectance for a sample at temperature  $T_S$  when irradiated by the surrounding cavity walls at  $T_H$ .

$\tau(T_S, T_H)$  = transmittance of a polyethelene compensating filter used to modify the spectral distribution of radiant energy reaching the detector.

$\sigma$  = Stefan - Boltzmann constant.

$C$  = a term used to include all other sources of emitted or reflected energy reaching the detector.

Similarly, when the surface is exposed to the colder cavity:

$$I_{S_C} = \epsilon_S (T_S) \tau (T_S) \sigma T_S^4 + \rho_S (T_S, T_C) \tau (T_S, T_C) \sigma T_C^4 + C. \quad (2)$$

Equations (1) and (2) show that only the reflected energy varies with this alternate irradiation by the two semicylinders. The detector amplifying system is made to respond only to the alternating signal arising in the reflectance terms (ref. 4) so that the fluctuating portion of the signal is the difference between equations (1) and (2). That is:

$$K V_S = I_{S_H} - I_{S_C} = \rho_S (T_S, T_H) \tau (T_S, T_H) \sigma T_H^4 - \rho_S (T_S, T_C) \tau (T_S, T_C) \sigma T_C^4 \quad (3)$$

where the voltage,  $V_S$ , of the output signal is proportional ( $K$ ) to the energy difference. Equation (3) represents the case for an unknown sample covering the opening of the sensing head. It is necessary to calibrate the instrument by establishing known voltage levels to define the range of the output signal. This is done using high and low reflectance standards resulting in the following intensity equations for each case:

$$K V_{100} = \rho_{100} (T_S, T_H) \tau (T_S, T_H) \sigma T_H^4 - \rho_{100} (T_S, T_C) \tau (T_S, T_C) \sigma T_C^4 \quad (4)$$

$$K V_0 = \rho_0 (T_S, T_H) \tau (T_S, T_H) \sigma T_H^4 - \rho_0 (T_S, T_C) \tau (T_S, T_C) \sigma T_C^4. \quad (5)$$

Here  $\rho_{100} (T_S, T_H)$  and  $\rho_0 (T_S, T_H)$  are the reflectances of the high and low standards, respectively and  $V_{100}$  and  $V_0$  are the corresponding voltages of the output signal.

If the high and low reflectance standards have no spectral variation in reflectance over the wavelength range specified by the planckian distributions for

$\sigma T_H^4$ ,  $\sigma T_C^4$  and  $\sigma T_S^4$ , and the surface properties of the materials are invariant over the temperature range of  $T_H$ ,  $T_C$ , and  $T_S$ , then the references are "grey" reflectors.<sup>5</sup>

That is:

$$\rho_{100}(T_S, T) \sigma T^4 = \rho_{100}(T_S) \sigma T^4$$

and

$$\rho_0(T_S, T) \sigma T^4 = \rho_0(T_S) \sigma T^4$$

Equations (4) and (5) then become

$$K V_{100} = \rho_{100}(T_S) [\tau(T_S, T_H) \sigma T_H^4 - \tau(T_S, T_C) \sigma T_C^4] \quad (6)$$

$$K V_0 = \rho_0(T_S) [\tau(T_S, T_H) \sigma T_H^4 - \tau(T_S, T_C) \sigma T_C^4]. \quad (7)$$

The measured reflectance is given by

$$\rho_S(T_S, T_H, T_C) = \frac{V_S - V_0}{V_{100} - V_0} \quad (8)$$

Substituting equations (3), (6) and (7) into the above gives for the measured reflectance:

$$\rho_S(T_S, T_H, T_C) = \frac{[\rho_S(T_S, T_H) \tau(T_S, T_H) \sigma T_H^4 - \rho_S(T_S, T_C) \tau(T_S, T_C) \sigma T_C^4] - \rho_0(T_S) [\tau(T_S, T_H) \sigma T_H^4 - \tau(T_S, T_C) \sigma T_C^4]}{[\rho_{100}(T_S) \tau(T_S, T_H) \sigma T_H^4 - \rho_{100}(T_S) \tau(T_S, T_C) \sigma T_C^4] - \rho_0(T_S) [\tau(T_S, T_H) \sigma T_H^4 - \tau(T_S, T_C) \sigma T_C^4]}$$

This reduces to:

$$\rho_S(T_S, T_H, T_C) = \frac{[\rho_S(T_S, T_H) \tau(T_S, T_H) \sigma T_H^4 - \rho_S(T_S, T_C) \tau(T_S, T_C) \sigma T_C^4]}{[\rho_{100}(T_S) \tau(T_S, T_H) \sigma T_H^4 - \rho_{100}(T_S) \tau(T_S, T_C) \sigma T_C^4]} - \frac{\rho_0(T_S)}{[\rho_{100}(T_S) - \rho_0(T_S)]} \quad (9)$$

When  $\rho_{100}(T_S)$  and  $\rho_C(T_S)$  are accurately known from independent measurements, the voltages  $V_{100}$  and  $V_0$  can be proportionately scaled so that  $\rho_{100}(T_S) \simeq 100\%$  and  $\rho_0(T_S) \simeq 0\%$ . Equation (9) then reduces to:

$$\rho_S(T_S, T_H, T_C) = \frac{[\rho_S(T_S, T_H)\tau(T_S, T_H)\sigma T_H^4 - \rho_S(T_S, T_C)\tau(T_S, T_C)\sigma T_C^4]}{[\tau(T_S, T_H)\sigma T_H^4 - \tau(T_S, T_C)\sigma T_C^4]} \quad (10)$$

If, by chance,  $\rho_S(T_S, T_H, T_C)$  is also the reflectance of a "grey" surface such that

$$\rho_S(T_S, T) \sigma T^4 = \rho_S(T_S) \sigma T^4$$

as defined previously, then equation (10) reduces further to

$$\rho_S(T_S, T_H, T_C) = \rho_S(T_S) \quad (11)$$

That is, for a grey reflector, the reflectance determined in this measurement is equal to the true reflectance by definition.

Equation (11) represents a special case. The more general expression of equation (10) includes the possibility of a sample whose spectral reflectance is non-grey. It would be erroneous to assume that equation (11) is valid for all samples and that the measured reflectance is the true reflectance. Such an assumption would permit the measurement to be compromised by the so-called "non-grey error."

To include the more general "non-grey" case, the parameters of equation (10) are replaced by their wavelength dependent equivalents. Equation (10) then becomes:



$$\rho_S(T_S, T_H, T_C) = \frac{\int_0^\infty \rho_\lambda(T_S) \tau_\lambda(T_S) E_\lambda(T_H) d\lambda - \int_0^\infty \rho_\lambda(T_S) \tau_\lambda(T_S) E_\lambda(T_C) d\lambda}{\int_0^\infty \tau_\lambda(T_S) E_\lambda(T_H) d\lambda - \int_0^\infty \tau_\lambda(T_S) E_\lambda(T_C) d\lambda} \quad (12)$$

where  $\sigma T^4 = \int_0^\infty E_\lambda(T) d\lambda$  and  $E_\lambda(T)$  is the planckian spectral irradiance function for a blackbody at temperature  $T$ .

Equation (12) can be written:

$$\rho_S(T_S, T_H, T_C) = \frac{\int_0^\infty \rho_\lambda(T_S) \tau_\lambda(T_S) [E_\lambda(T_H) - E_\lambda(T_C)] d\lambda}{\int_0^\infty \tau_\lambda(T_S) [E_\lambda(T_H) - E_\lambda(T_C)] d\lambda} \quad (13)$$

This shows that the measured reflectance is equal to the integrated true spectral reflectance modified by the indicated weighting function. By definition, the true weighted reflectance of a surface at temperature  $T_S$  is given by

$$\rho_S(T_S) = \frac{\int_0^\infty \rho_\lambda(T_S) E_\lambda(T_S) d\lambda}{\int_0^\infty E_\lambda(T_S) d\lambda} \quad (14)$$

The difference between the true reflectance and the measured reflectance is the measurement error, which can be defined as:

$$\delta \rho_S = \rho_S(T_S) - \rho_S(T_S, T_H, T_C) \quad (15)$$

and

$$\delta \rho_S = \frac{\int_0^\infty \rho_\lambda(T_S) E_\lambda(T_S) d\lambda}{\int_0^\infty E_\lambda(T_S) d\lambda} - \frac{\int_0^\infty \rho_\lambda(T_S) \tau_\lambda(T_S) [E_\lambda(T_H) - E_\lambda(T_C)] d\lambda}{\int_0^\infty \tau_\lambda(T_S) [E_\lambda(T_H) - E_\lambda(T_C)] d\lambda} \quad (16)$$

A summation technique is used to evaluate the integrals of equation (16).

Equation (13) may be rewritten to give:

$$\rho_S(T_S, T_H, T_C) = \sum_{n=1}^m \rho_{\Delta\lambda_n}(T_S) q_n$$

where

$$q_n = \frac{\tau_{\Delta\lambda_n}(T_S)[E_{\Delta\lambda_n}(T_H) - E_{\Delta\lambda_n}(T_C)]}{\sum_{n=1}^m \tau_{\Delta\lambda_n}(T_S)[E_{\Delta\lambda_n}(T_H) - E_{\Delta\lambda_n}(T_C)]}$$

Here  $\rho_{\Delta\lambda_n}$ ,  $\tau_{\Delta\lambda}$  and  $E_{\Delta\lambda}$  are defined over a wavelength band  $\Delta\lambda$  rather than at a discrete wavelength  $\lambda$ . The summation is over the range  $0 \leq \lambda \leq \infty$  and consequently, if  $m$  is large, each  $\Delta\lambda_n$  will be small. Accuracy dictates the choice of  $\Delta\lambda$ , since the summation must follow the wavelength variation of each parameter in the integral. In a similar manner, equation (14) may be written:

$$\rho_S(T_S) = \sum_{n=1}^m \rho_{\Delta\lambda_n}(T_S) p_n$$

where

$$p_n = E_{\Delta\lambda_n} / \sigma T_S^4$$

It is now possible to express the measurement error defined by equation (16) in terms of the summations presented above. That is:

$$\delta \rho_S = \sum_{n=1}^m \rho_{\Delta\lambda_n}(T_S) p_n - \sum_{n=1}^m \rho_{\Delta\lambda_n}(T_S) q_n$$

or

$$\delta \rho_s = \sum_{n=1}^m \rho_{\Delta\lambda_n}(T_s) (p_n - q_n). \quad (17)$$

$p_n$  and  $q_n$  were each calculated. Equations (16) and (17) show that the measurement error is contained within the difference between the two weighting functions and if they were equal there would be no error. The presence of the term  $\tau_{\lambda}(T_s)$  is justified by the fact that it reduces the difference between the two weighting functions. In most cases the surface whose emittance is to be determined is at room temperature, so that  $T_s \simeq 300^\circ\text{K}$ . The cavity temperatures are controlled at  $T_H \simeq 315^\circ\text{K}$  and  $T_C \simeq 305^\circ\text{K}$ . The difference between  $E_{\lambda}(300^\circ\text{K})$  and  $[E_{\lambda}(315^\circ\text{K}) - E_{\lambda}(305^\circ\text{K})]$  is largest at the shorter wavelengths, so if a selective filter is used, such as black polyethelene, this difference can be minimized. The spectral transmittance,  $\tau_{\lambda}(T_s)$ , of the black polyethelene compensating filter is given in figure 1 for the range 2.5 to 40 microns.  $E_{\Delta\lambda}(T_s)$  and  $[E_{\Delta\lambda}(315^\circ\text{K}) - E_{\Delta\lambda}(305^\circ\text{K})]$  were determined from a set of radiation tables.<sup>6</sup> To simplify the calculations only 20  $\Delta\lambda_n$  (ie  $m = 20$  in eq 17) were chosen with particular emphasis given to the wavelength region that is important for a  $300^\circ\text{K}$  blackbody. The resulting values of  $p_n$ ,  $q_n$  and  $(p_n - q_n)$  are given in table 1.

The wavelength dependence of  $(p_n - q_n)$ , from which the non-grey error arises, is plotted in figure 2. The effect of the compensating filter in reducing the difference between the weighting functions is shown by the dotted curve of figure 2 which resulted from removing  $\tau_{\Delta\lambda}(T_s)$  from the equations used to calculate  $p_n$  and  $q_n$ . From equation (17) and figure 2 it is evident that  $\delta \rho_s$  is large for a sample having high reflectance at those wavelengths where  $(p_n - q_n)$  is large. If the spectral reflectance is unknown beforehand, as is generally the case, a significant error can be recorded.

Since  $p_n$  and  $q_n$  are normalized functions whose integrals are unity, the sum of their differences is zero. That is:

$$\sum_{n=1}^m (p_n - q_n) = 0$$

Therefore, when a surface has a reflectance that is invariant with wavelength and  $\rho_{\Delta\lambda_n}(T_s)$  is a constant in equation (17), then  $\delta\rho_s = 0$ . This is the case for a grey sample and the conditions of equation (11) apply.

## RESULTS

The equations derived above are in terms of reflectance, both spectral,  $\rho_\lambda(T_s)$ , and total,  $\rho(T_s)$ . Using Kirchoff's relation, it is possible to express the measurement error in terms of emittance. Since

$$\epsilon_\lambda(T_s) = 1 - \rho_\lambda(T_s) - \tau_\lambda(T_s),$$

it follows that

$$\delta \epsilon_s(T_s) = - \delta \rho_s(T_s) \quad (18)$$

for an opaque surface.

The difference between the measured emittance and true emittance is presented in figure 3 for two hypothetical cases of extreme spectral selectivity demonstrated by the two inserted curves. Different emittances were obtained by varying the wavelength at which the step occurred in each reflectance spectrum. The error was calculated from equations (17) and (18) with the aid of table 1. It is evident that the influence of the modifying filter reduces the maximum non-grey error to a tolerable level even for these extreme cases.

To observe how the error appears in a more practical case, consider the reflectance curves shown in figure 4. These curves demonstrate the thickness dependence of the infrared reflectance of vapor deposited aluminum coated with various thicknesses of reactively deposited silicon oxide. This material has been used as a thermal control surface on many satellites and the results of a detailed study of its properties have been presented in a recent publication.<sup>2</sup> The data were obtained from specular reflectance measurements performed on a Perkin - Elmer 621 spectrophotometer and were used in conjunction with equations (17) and 18) to calculate the magnitude of the non-grey error present in the total emittance measurement. The calculated error is shown in figure 5 for samples consisting of evaporated aluminum coated with various silicon oxide thicknesses.

In order to compare the magnitude of the calculated error with one determined empirically, spectral reflectance data for various samples were used with equations (14) and (18) to obtain a "true emittance." Emittance values obtained in this manner are not subject to the non-grey error. Table 2 compares total emittance values measured directly, before and after correction for the non-grey error, with emittance values determined from weighted spectral reflectance measurements. The Alzak data shown in table 2 were obtained from a Gier - Dunkle heated cavity reflectometer used with a Beckman IR-7 spectrophotometer to provide infrared spectral reflectances of diffuse surfaces. The Alzak coating is the result of an anodic deposition of aluminum oxide onto an aluminum surface.<sup>7</sup> It employs the same principle as described earlier for the silicon oxide overcoated aluminum to give a thickness dependent  $\alpha/\epsilon_T$  and was used as the thermal control surface on the Orbiting Astronomical Observatory.

Table 2 shows that the difference between spectrally determined total emittances and those determined directly is reduced when the calculated correction for the non-grey error is applied to the total emittance data. The lack of perfect agreement indicates the need for a better choice of weighting function in equation (13) as well as the presence of other undefined instrumental errors. However, the data does empirically verify the presence of the non-grey error in the total emittance measurement.

## CONCLUSIONS

It is apparent from these results that it is not possible to eliminate the non-grey error using calibration techniques with instrumentation that is currently available when the dielectric film thickness varies in an unknown manner. Calibration would require that the infrared spectral reflectance of the measured surface be known and this would defeat from the start the requirement for a rapid determination of total emittance. In general, it is either impossible or impractical to perform infrared spectral reflectance measurements on coated satellite surfaces once they have been assembled. Therefore, the only recourse is to calculate the magnitude of the non-grey error as it appears in a given type of instrument for a particular class of samples in order that the total emittance measurements may be corrected accordingly.

A calibrated total emittance measuring device could still be used to monitor the uniformity of oxide thickness over a large area, since the emittance of the oxide coated surface is thickness dependent, but in this application it would compete with other available optical techniques. Of course, if the dielectric film thickness is known from the beginning, the only need for an independent determination of emittance is to provide assurance that the surface properties haven't changed during assembly and storage in which case calibration is unnecessary.

## REFERENCES

- 1) Drummeter, L. F., Jr., and Hass, G., "Solar Absorptance and Thermal Emittance of Evaporated Coatings," Physics of Thin Films, Vol. 2, ed. by G. Hass and R. E. Thun, Academic Press, New York, 1964, pp 305-361.
- 2) Bradford, A. P., Hass, G., Heaney, J. B. and Triolo, J. J., "Solar Absorptivity and Thermal Emissivity of Aluminum Coated With Silicon Oxide Films Prepared by Evaporation of Silicon Monoxide," to be published in Applied Optics, Feb. 1970.
- 3) Edwards, D. K. and Nelson, K. E., "Maximum Error in Total Emissivity Measurements Due to Non-Grayness of Samples," ARS Journal, Vol. 31, 1961, pp. 1021-1022.
- 4) Nelson, K. E., Luedke, E. E., and Bevans, J. T., "A Device for the Rapid Measurement of Total Emittance," J. Spacecraft, Vol. 3, No. 5, May 1966, pp. 758-760.
- 5) Jakob, M., Heat Transfer, Vol. 1, John Wiley and Sons, New York, 1949, p. 41.
- 6) Stevenson, G. T., "Black-Body Radiation Functions," NAVWEPS Report 7621, U. S. Naval Ordnance Test Station, China Lake, California, May 1963.
- 7) Andrus, J. M. and Pettit, R., "Chemical Preparation of Aluminum for Chemical, Electrochemical Brightening and Anodic Coating," Anodized Aluminum, ASTM STP 388, American Society For Testing and Materials, Philadelphia, Pa., Feb 1965, pp. 1-20.

## FIGURE CAPTIONS

- Figure 1. Infrared transmittance of black polyethelene filter.
- Figure 2. Effect of the modifying filter on the spectral distribution of the difference between weighting functions.
- Figure 3. Effect of extreme spectral selectivity on the accuracy of measured total emittance.
- Figure 4. Infrared reflectance of aluminum coated with reactively deposited silicon oxide of various thicknesses.
- Figure 5. Calculated error in total emittance as a function of silicon oxide thickness.



TABLE 1

 $p_n, q_n$  and  $p_n - q_n$  for  $1 \leq n \leq 20$ 

$n$	$\Delta\lambda(\mu m)$	$p_n$	$q_n$	$p_n - q_n$
1	0-2	0.0000	0.0000	0.0000
2	2-4	0.0021	0.0026	-0.0005
3	4-6	0.0373	0.0665	-0.0292
4	6-8	0.1010	0.0942	0.0068
5	8-10	0.1331	0.1554	-0.0223
6	10-12	0.1304	0.1633	-0.0329
7	12-14	0.1124	0.1067	0.0057
8	14-16	0.0915	0.0777	0.0138
9	16-18	0.0727	0.0731	-0.0004
10	18-20	0.0575	0.0533	0.0042
11	20-22	0.0453	0.0398	0.0055
12	22-24	0.0360	0.0296	0.0064
13	24-26	0.0287	0.0250	0.0037
14	26-28	0.0232	0.0194	0.0038
15	28-30	0.0188	0.0158	0.0030
16	30-32	0.0153	0.0145	0.0008
17	32-34	0.0127	0.0069	0.0058
18	34-36	0.0106	0.0079	0.0027
19	36-38	0.0088	0.0082	0.0006
20	38- $\infty$	0.0625	0.0398	0.0227
$\sum_{n=1}^{20} =$		0.9999	0.9997	0.0002

TABLE 2

Near Normal Total Emittance\* at 300°K

Sample	Oxide Thickness ( $\mu\text{m}$ )	Determined Directly		Deduced From Spectral Measurements
		Uncorrected	Corrected	
Evaporated Al	0.172	0.013	0.011	0.013
coated with	0.358	0.030	0.028	0.025
reactively	1.11	0.245	0.221	0.222
deposited	1.48	0.385	0.360	0.359
silicon oxide	1.94	0.455	0.443	0.445
	2.32	0.510	0.505	0.525
	3.06	0.555	0.558	0.583
ALZAK	2.5	0.680	0.682	0.69
	5.0	0.73	0.75	0.78

\* The third decimal place in the total emittance data is given only to illustrate the trend of the correction and is indicative of the reproducibility but not the accuracy of the measurements.

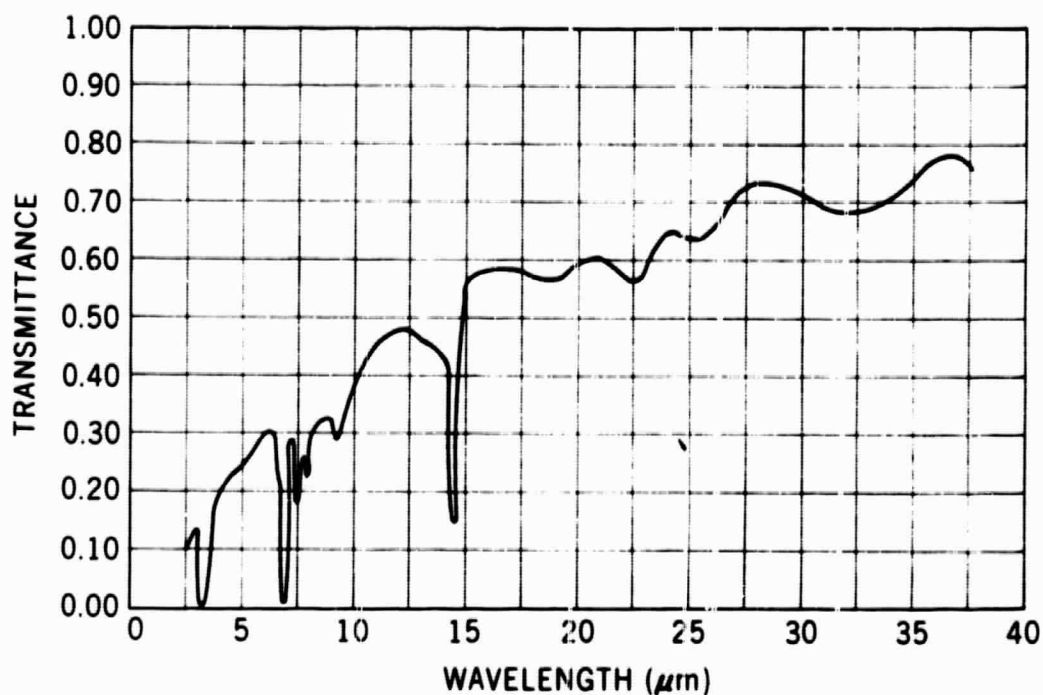


Figure 1. Infrared transmittance of black polyethylene filter.

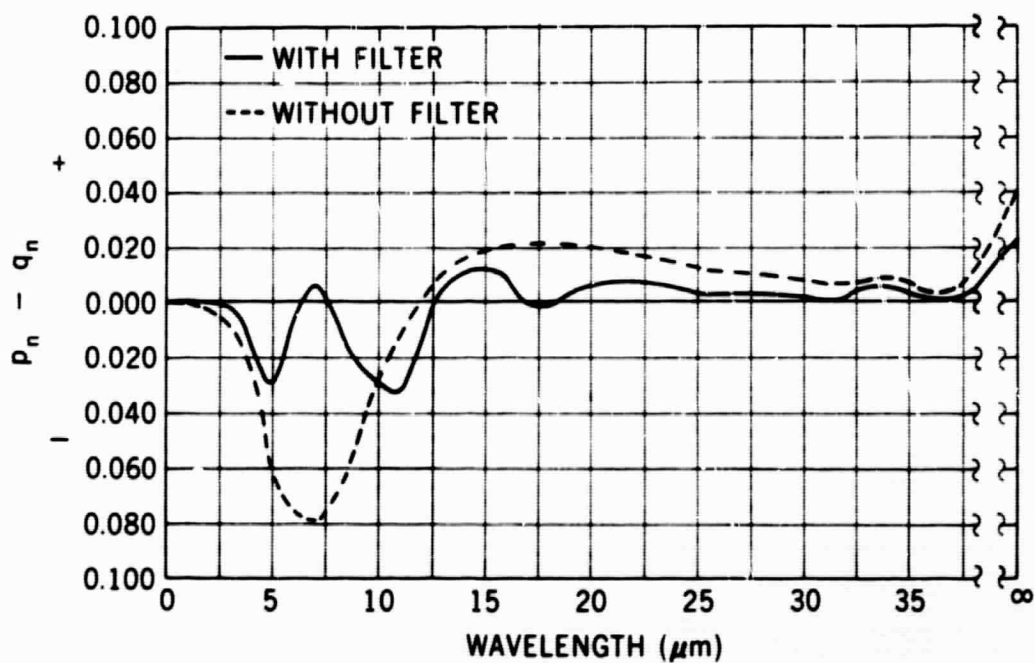


Figure 2. Effect of the modifying filter on the spectral distribution of the difference between weighting functions.

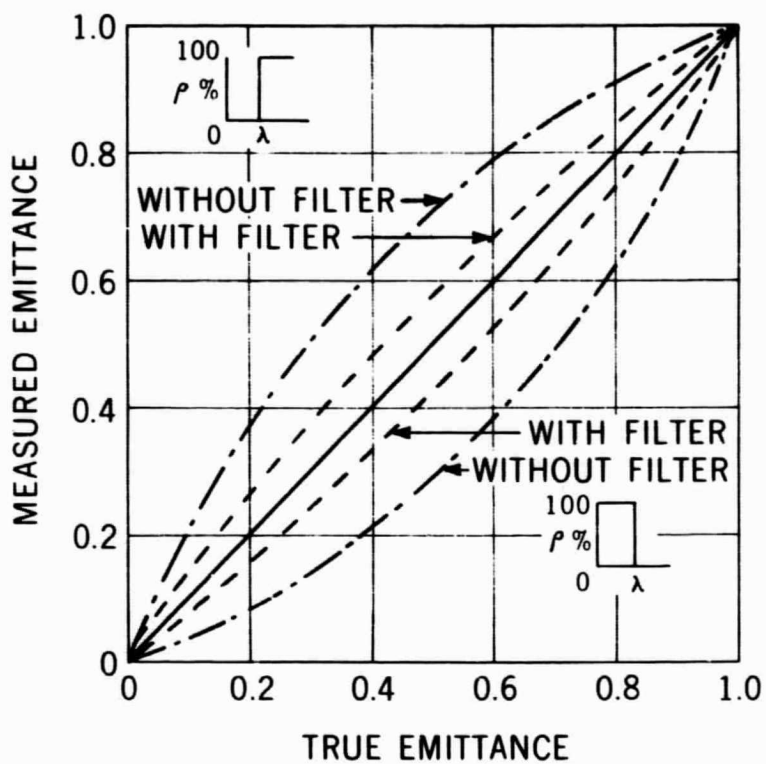


Figure 3. Effect of extreme spectral selectivity on the accuracy of measured total emittance.

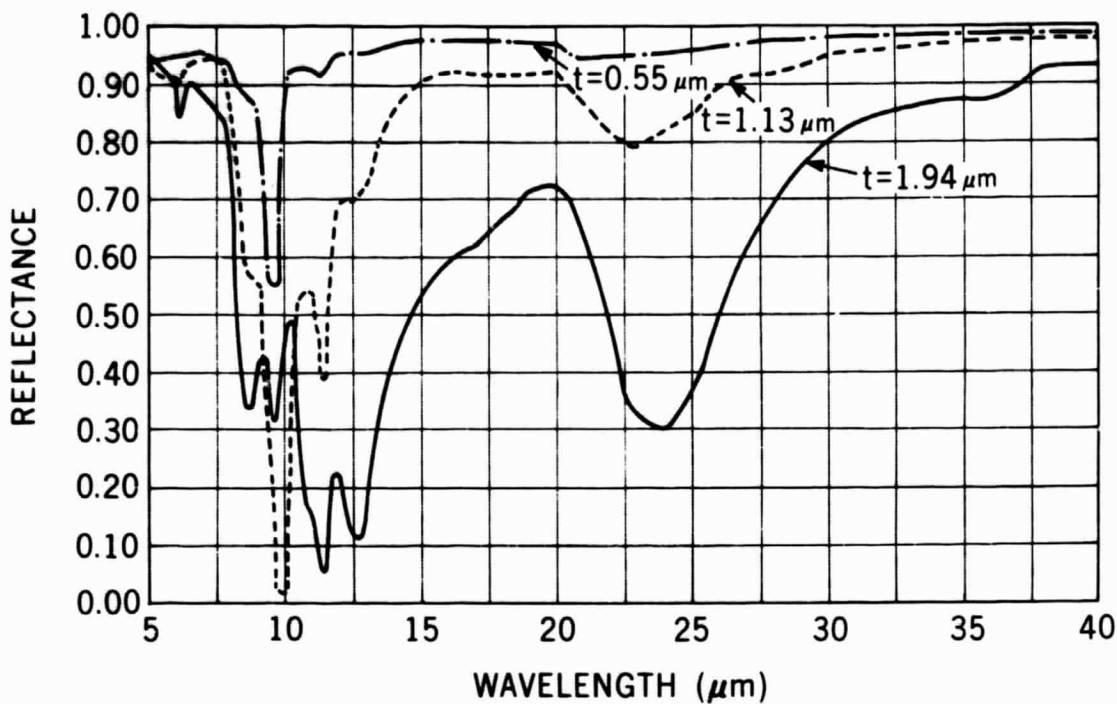


Figure 4. Infrared reflectance of aluminum coated with reactively deposited silicon oxide of various thicknesses .

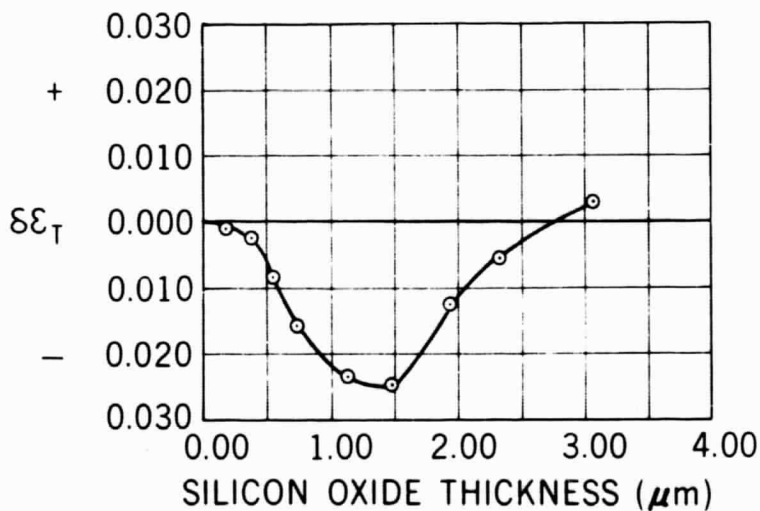


Figure 5. Calculated error in total emittance as a function of silicon oxide thickness .